HIGH VALUE MULTILAYER CERAMIC CAPACITORS BJ -25~+85°C RL X7B -55~+125°C

大容量積層セラミックコンデンサ

500		BJ	-25~+85°C			
	BJ	X7R	-55~+125°C			
OPERATING TEMP.		X5R −55~+85°C				
	F	F	-25~+85°C			
		Y5V	′ −30~+85℃			



特長 FEATURES

- ・電極にNi金属を使用し、端子電極部にメッキをしてあることにより、はんだ付け性および耐熱性にすぐれ、マイグレーションもほとんど発生せず、高い信頼性を示します
- ・等価直列抵抗(ESR)が小さく、ノイズ吸収性にすぐれています。特にタンタルおよびアルミ電解コンデンサに比較した場合
- ・高い許容リップル電流値
- ・高い定格電圧でありながら小型形状
- ・絶縁抵抗、破壊電圧が高く信頼性にすぐれる 等の特徴があります

- The use of Nickel(Ni) as material for both the internal and external electrodes improves the solderability and heat resistance characteristics. This almost completely eliminates migration and raises the level of reliability significantly.
- Low equivalent series resistance(ESR) provides excellent noise absorption characteristics.
- Compared to tantalum or aluminum electrolytic capacitors these ceramic capacitors offer a number of excellent features, including:

Higher permissible ripple current values

Smaller case sizes relative to rated voltage

Improved reliability due to higher insulation resistance and break-down voltage.

用途 APPLICATIONS

- ・デジタル回路全般
- ・電源バイパスコンデンサ 液晶モジュール用 液晶駆動電圧ライン用 電源電圧の高いLSI、IC、OPアンプ用
- ・平滑コンデンサ DC-DCコンバータ(入力、出力側用) スイッチング電源(2次側用)

- · General digital circuit
- Power supply bypass capacitors
 Liquid crystal modules
 Liquid crystal drive voltage lines
 LS I, I C, converters(both for input and output)
- Smoothing capacitors DC-DC converters (both for input and output) Switching power supplies (secondary side)

形名表記法 ORDERING CODE

4



2	
シリー	·ズ名
М	積層コンデンサ

U	
端子電	極
K	メッキ品

形状寸法(E	$IA)L\times W(mm)$
107(0603)	1.6×0.8
212(0805)	2.0×1.25
316(1206)	3.2×1.6
325(1210)	3.2×2.5
432(1812)	4.5×3.2
550(2220)	5.7×5.0

温度特	性(%)
△F	± 30 ± 80
BJ	±10
6	△= スペース

U	
公称前	電容量 (pF)
例	
473	47,000
105	1,000,000

7		
容量許	容差	
K	±10	%
M	±20	%
Z	± 80 ± 20	%

8	
製品厚	[み (mm)
A	0.8
D	0.85
F	1.15
G	1.25
Н	1.5
L	1.6
N	1.9
M	2.5

個別仕	:様
_	標準
10	
包装	
В	単品(袋づめ)
Т	リールテーピング
1	
当社管	理記号
	標准品

J M	K	3	1	6	В	J	1	0	6	M	L	_	Т	\bigcirc
0 3	3		4					6		7	8	9	10	

6

Rated	voltage(VDC)
Α	4
J	6.3
L	10
E	16
Т	25
G	35
U	50

2	
Series	s name
М	Multilayer cerami
IVI	capacitors



4	
Dimensions(ca	ase size)(mm)
107(0603)	1.6×0.8
212(0805)	2.0×1.25
316(1206)	3.2×1.6
325(1210)	3.2×2.5
432(1812)	4.5×3.2
550(2220)	5.7×5.0

_								
Temperature characteristics code								
△F	Y5V	-30~+85℃ +22/-82%						
BJ	X7R	-55~+125℃ ±15%						
ВЈ	X5R	-55~+85℃ ±15%						
		A Blank anges						

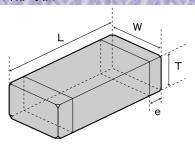
6	•
Nomin	al capacitance(pF)
example	
473	47,000
105	1,000,000

7							
Capacitance tolerances(%)							
K	±10						
М	±20						
Z	± 80 ± 20						
	± 20						

8									
Thickr	Thickness(mm)								
Α	0.8								
D	0.85								
F	1.15								
G	1.25								
Н	1.5								
L	1.6								
N	1.9								
М	2.5								

9										
Specia	Special code									
	Standard products									
10										
Packa	ging									
В	Bulk									
Т	Tape & reel									
1										
Interna	Internal code									
Δ	Standard products									
	△=Blank space									

外形寸法 EXTERNAL DIMENSIONS



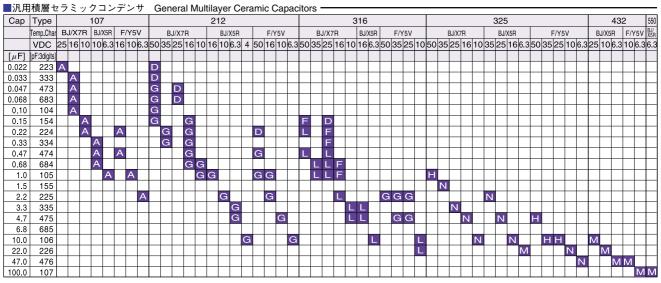
Type(EIA)	L	W	Т		е	
□MK107	1.6±0.10	0.8±0.10	0.8±0.10	A	0.35±0.25	
(0603)	(0.063±0.004)	(0.031±0.004)	(0.031±0.004)	_ A	(0.014±0.010)	
			0.85±0.10	D		
☐MK212	2.0±0.10	1.25±0.10	(0.033±0.004)		0.5±0.25	
(0805) *1	(0.079±0.004)	(0.049 ± 0.04)	1.25±0.10	G	(0.020 ± 0.010)	
` *2			(0.049±0.004)			
			0.85±0.10	D		
			(0.033±0.004)			
			1.15±0.10	F	+0.35	
☐MK316	3.2±0.15	1.6±0.15	(0.045±0.004)		0.5 +0.35	
(1206)	(0.126±0.006)	(0.063±0.006)	1.25±0.10	G	$(0.020^{+0.014}_{-0.010})$	
			(0.049±0.004)	_ <u>~</u>		
			1.6±0.20	L		
			(0.063±0.008)	_	—	
	3.2±0.30		0.85±0.10	р	0.6±0.3	
		2.5±0.20	(0.033±0.004)			
			1.15±0.10	F		
			(0.045±0.004)	·		
□MK325			1.5±0.10	н		
(1210)	(0.126±0.012)	(0.098 ± 0.008)	(0.059±0.004)		(0.024±0.012)	
			1.9±0.20	N		
			(0.075±0.008)			
			2.5±0.20	М		
			(0.098±0.008)			
□MK432	4.5±0.40	3.2±0.30	2.5±0.20	М	0.9±0.6	
(1812)	(0.177±0.016)	(0.126±0.012)	(0.098±0.008)		(0.035±0.024)	
□MK550	5.7±0.40	5.0±0.3	2.5±0.20	М	0.3~2.0	
(2220)	(0.224±0.016)	(0.197±0.012)	(0.098±0.008)		(0.012~0.079)	

Note: *1. Including dimension tolerance ±0.2mm (±0.008inch). *2. Including dimension tolerance ±0.15mm (±0.006inch)

注: *1. ±0.2mm交差、*2. ±0.15mm交差あり

Unit: mm (inch)

概略バリエーション AVAILABLE CAPACITANCE RANGE



■低背積層セラミックコンデンサ Low profile Multilayer Ceramic Capacitors

	EXAMENDED TO THE INTERNATION OF THE PROPERTY O												
Cap	Type		21	12			3	316 325					
	Temp.Char	BJ/	X7R	F/Y	′5V	BJ/X7R	BJ/X5R	F/Y	′5V	BJ/X7R	BJ/X5R	F/Y	5V
	VDC	16	10	10	6.3	10	6.3	10	6.3	10	6.3	16	10
[μF]	[pF:3digits]												
0.47	474	D											
0.68	684	D											
1.0	105		D										
2.2	225			D		D							
3.3	335					F	D			D			
4.7	475				D		D	D		F			
6.8	685						F						
10.0	106							F	D		D	F	
22.0	226												F

			温度特性					
温度特性コード			Temperature chara	acteristics		静電容量許容差(%)	tanδ(%)	
Temp. char.Code	準拠規格		温度範囲(℃)	基準温度(℃)	静電容量変化率(%)	Capacitance tolerance	Dissipation factor	
	Applicab	le standard	Temperature range	Ref. Temp.	Capacitance change			
BJ	JIS	BJ	-25~85	20	±10	±20(M)	2.5%max.**	
ь	EIA	X7R*	−55~125	25	±15	±10(K)	2.5 /oiliax.	
_	JIS	F	-25~85	20	+30 -80	+80 -20(Z)	7.00/***	
F	EIA	Y5V	−30~85	25	+22 -82	_20 (Z)	7.0%max.***	

★Some exceptions apply. Refer to the available capacitance range table for the parts which are only available in X5R.

★★3.5%max: LMKtype; 107type (C≤0.47 μ F), 212type (C≤1.0 μ F), 316/325/432type

EMKtype ; 107/212/316/325type TMKtype ; 316type (C>0.47 μ F), 325type, 432type

GMKtype; 212type, 316type, 325type

UMKtype ; 212type (C>0.1 μ F), 316type (C \geq 0.47 μ F), 325type

★ ★5.0%max : JMKtype ; 107type, 212type, 316type, 325type, 432type, 550type LMKtype ; 107type (C>0.47 μ F), 212type (C≥2.2 μ F)

★★10%max: AMKtype; 212type

★★★9%max:LMKtype; 212type, 汎用316type (C=10µF) 低背316type (C=4.7μF)

UMKtype; 325type 16%max: JMKtype; 107/212/316/325/432type

LMKtype; 107/325/432, 汎用316type (C>10 µF)

セレクションガイド Selection Guide

⋖ P.8









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etc

アイテム一覧 PART NUMBERS

■107TYPE (0603 case size) -

(.	7000 0000 0.20)	9						
定格電圧	形名		公 新電容量 Capacitance	温度特性 Temperature	tan δ Dissipation	実装条件 Soldering method R:リフロー Reflow soldering	静電容量 許容差 Capacitance	厚 み Thickness
RatedVoltage	Ordering code		[μ F]	characteristics	factor [%]Max.	W:7D — Wave soldering	•	[mm] (inch)
25V	TMK107BJ223□A		0.022		2.5			
	EMK107BJ333□A		0.033					
16V	EMK107BJ473□A		0.047					
100	EMK107BJ683□A		0.068	BJ/X7R		R,W	±10%	0.8±0.10
	EMK107BJ104□A		0.1		3.5	Π, ۷۷		
	LMK107BJ154□A		0.15				±20%	(0.031 ± 0.004)
	LMK107BJ224□A		0.22					
10V	LMK107BJ334□A		0.33					
	LMK107BJ474□A		0.47	BJ/X5R				
	LMK107BJ684□A		0.68	DJ/A3H	5	R		
6.3V	JMK107BJ105□A		1.0		3			
16V	EMK107F224ZA		0.22		7	R,W		
100	EMK107F474ZA		0.47	F/Y5V	,	Π, ۷۷	+80%	0.8 ± 0.10
10V	LMK107F105ZA		1.0	1/150	16	R	-20%	(0.031 ± 0.004)
6.3V	JMK107F225ZA		2.2		.0	n		

形名の□には静電容量許容差記号が入ります。 □ Please specify the capacitance tolerance code.

■212TYPE (0805 case size)

■2121YPE (0	ous case size) —						
定格	形名	公 新 新 新 新 新	温度特性	$tan \delta$	実装条件	静電容量 許容差	厚み
電圧			Temperature	Dissipation	Soldering method		Thickness
RatedVoltage	Ordering code	Capacitance	characteristics	factor	R:リフロー Reflow soldering	Capacitance	[mm] (inch)
- I latou v ortago	Ordoning code	[μF]		[%]Max.	W:フロー Wave soldering	tolerance	[IIIII] ()
	UMK212BJ223□D	0.022					0.85±0.1
	UMK212BJ333□D	0.033					(0.033±0.004)
50V	UMK212BJ473□G	0.047		2.5			
50 V	UMK212BJ683□G	0.068					
	UMK212BJ104□G	0.1					1.25±0.1
	UMK212BJ154□G	0.15					(0.049±0.004)
05)/	GMK212BJ224□G	0.22		3.5			
35V	GMK212BJ334□G	0.33	BJ/X7R				
25V	TMK212BJ473□D	0.047	20,71,711	0.5	R,W	±10% ±20%	0.85±0.1
25V	TMK212BJ683□D	0.068		2.5			(0.033±0.004)
	EMK212BJ154□G	0.15					
	EMK212BJ224□G	0.22					
16V	EMK212BJ334□G	0.33					1.25±0.1
167	EMK212BJ474□G	0.47		3.5			
	EMK212BJ684□G	0.68					
	EMK212BJ105□G	1.0	BJ/X5R				(0.049±0.004)
	LMK212BJ684□G	0.68	BJ/X7R				
10V	LMK212BJ105□G	1.0	DJ/X/TI	ı			
	LMK212BJ225MG	2.2					
0.01/	JMK212BJ335MG	3.3	BJ/X5R	5	R	1.0007	1.25±0.15
6.3V	JMK212BJ475MG	4.7	DJ/ASH		l n	±20%	(0.049±0.006)
4V	AMK212BJ106MG	10		10			1.25±0.20(0.049±0.008)
	UMK212F224ZD	0.22					0.85±0.1(0.033±0.004)
50V	UMK212F474ZG	0.47					
	UMK212F105ZG	1.0		7	R,W	+80%	
16)/	EMK212F105ZG	1.0	F/Y5V				1.25±0.1
16V —	EMK212F225ZG	2.2				-20%	(0.049±0.004)
10V	LMK212F475ZG	4.7		9			(3.0 10 = 0.00 +)
6.3V	JMK212F106ZG	10	[16	R		

形名の□には静電容量許容差記号が入ります。 □ Please specify the capacitance tolerance code.

■316TYPE(1206 case size) —

		公 称		tan δ	実装条件	静電容量	E 7.
定格	形 名	カー が 静電容量	温度特性	lallo		許容差	厚み
電圧		所电台里 Capacitance	Temperature	Dissipation	Soldering method	Capacitance	Thickness
RatedVoltage	Ordering code	· .	characteristics	factor	R:リフロー Reflow soldering W:フロー Wave soldering	tolerance	[mm] (inch)
	LIMICOLOD ILEADE	[μF]		[%]Max.	Vi. 7 H Wave soluting	tolerance	
501/	UMK316BJ154 F	0.15		2.5			1.15±0.1 (0.045±0.004)
50V	UMK316BJ224 L	0.22			_		
	UMK316BJ474□L	0.47					1.6±0.2 (0.063±0.008)
35V	GMK316BJ684□L	0.68		3.5			
	GMK316BJ105□L	1.0					
	TMK316BJ154□D	0.15					0.85±0.1 (0.033±0.004)
	TMK316BJ224□ F	0.22	BJ/X7R	2.5	R,W	±10%	1.15±0.1 (0.045±0.004)
25V	TMK316BJ334□F	0.33		2.5		±20%	(0.0.10=0.00.1)
25 V	TMK316BJ474□L	0.47					
	TMK316BJ684□L	0.68					1.6±0.2 (0.063±0.008)
	TMK316BJ105□L	1.0					
	EMK316BJ684□ F	0.68					4.45.4.4.40.45.40.004)
	EMK316BJ105□ F	1.0					1.15±0.1 (0.045±0.004)
16V	EMK316BJ225ML	2.2					
	EMK316BJ335ML	3.3	BJ/X5R	3.5			
	EMK316BJ475ML	4.7	- DJ/ASH			±20%	
4014	LMK316BJ335ML	3.3	BJ/X7R		R	±20%	1.6±0.2 (0.063±0.008)
10V	LMK316BJ475ML	4.7	DJ/A/R				
6.3V	JMK316BJ106ML	10	BJ/X5R	5			
50V	UMK316F225ZG	2.2			R,W		
051/	GMK316F225ZG	2.2			n,vv		
35V	GMK316F475ZG	4.7		7	R	+80%	1.25±0.1 (0.049±0.004)
051/	TMK316F225ZG	2.2	F/Y5V		R,W	-20%	,
25V	TMK316F475ZG	4.7					
10V	LMK316F106ZL	10	1	9	R		1 0 1 0 0 (0 000 1 0 000)
100	LMK316F226ZL	22	1	16	1		1.6±0.2 (0.063±0.008)

形名の□には静電容量許容差記号が入ります。 □ Please specify the capacitance tolerance code.

■325TYPE(1210 case size) -

■32311FL(12	210 case size) ———						
定格	形名	公 称	温度特性	$\tan\delta$	実装条件	静電容量	厚み
電圧	<i>N</i> 4	静電容量	Temperature	District of	Soldering method	許容差	Thickness
RatedVoltage	Ordering code	Capacitance	characteristics	Dissipation factor	The 7 The Troilow Goldening	Capacitance	[mm] (inch)
	Ordering code	[μF]		[%]Max.	W:フロー Wave soldering	tolerance	[IIIII] (IIIOII)
50V	UMK325BJ105□H	1.0	BJ/X7R		R,W	±10% ± 20%	1.5±0.1 (0.059±0.004)
35V	GMK325BJ155MN	1.5	DJ/X/N				
357	GMK325BJ225MN	2.2	BJ/X5R				
	TMK325BJ335MN	3.3	BJ/X7R	3.5			
25V	TMK325BJ475MN	4.7	BJ/X5R		R	±20%	
16V	EMK325BJ475MN	4.7	BJ/X7R				1.9±0.2 (0.075±0.008)
	EMK325BJ106MN	10	BJ/X5R				
10V	LMK325BJ106MN	10	BJ/X7R				
6.3V	JMK325BJ226MM	22	BJ/X5R	5			2.5±0.2 (0.098±0.008)
50V	UMK325F475ZH	4.7		9			
35V	GMK325F106ZH	10		7			1.5±0.1 (0.059±0.004)
25V	TMK325F106ZH	10	F/Y5V	,	R	+80%	
10V	LMK325F226ZN	22		16		-20%	
6.3V	JMK325F476ZN	47		16			1.9±0.2 (0.075±0.008)

形名の \square には静電容量許容差記号が入ります。 \square Please specify the capacitance tolerance code.

アイテム一覧 PART NUMBERS

■432TYPE(1812 case size) —————

定格 電圧 RatedVoltage	形 名 Ordering code	公 静電容量 Capacitance [µF]	温度特性 Temperature characteristics	tactor	実装条件 Soldering method R:リフロー Reflow soldering W:フロー Wave soldering	静電容量 許容差 Capacitance tolerance	厚 み Thickness [mm] (inch)
25V	TMK432BJ106MM	10		3.5			
10V	LMK432BJ226MM	22	BJ/X5R	0.0	R	±20%	2.5±0.2 (0.098±0.008)
6.3V	JMK432BJ476MM	47		5			
10V	LMK432F476ZM	47	F/Y5V	16	R	+80%	2.5±0.2 (0.098±0.08)
6.3V	JMK432F107ZM	100	1/13	10	n	-20%	2.020.2 (0.00020.00)

■550TYPE(2220 case size) ————

定格電圧	形名	公 新電容量 Capacitance	温度特性 Temperature	tan δ	実装条件 Soldering method R:リフロー Reflow soldering	静電容量 許容差 Capacitance	厚 み Thickness
RatedVoltage	Ordering code	[μ F]	characteristics		W:7□ — Wave soldering		[mm] (inch)
6.3V	JMK550BJ107MM	100	BJ/X5R	5	R	±20%	2.5±0.2 (0.098±0.008)

アイテム一覧 PART NUMBERS

■212TYPE(08	805 case size) ——						
定格 電圧 RatedVoltage	形 名 Ordering code	公 称 静電容量 Capacitance [µF]	温度特性 Temperature characteristics		実装条件 Soldering method R:リフロー Reflow soldering W:フロー Wave soldering	Capacitance	厚 み Thickness [mm] (inch)
16V	EMK212BJ474□D	0.47			R, W	±10%	
100	EMK212BJ684□D	0.68	BJ/X7R	3.5	n, vv	±20%	0.85±0.1 (0.033±0.004
10V	LMK212BJ105□D	1.0			R	1 ±20%	
10V	LMK212F225ZD	2.2	F/Y5V	9	R	+80%	0.85±0.1 (0.033±0.004
6.3V	JMK212F475ZD	4.7	1/130	16	п	-20%	0.00=0.1 (0.000=0.001

形名の□には静電容量許容差記号が入ります。

■316TYPE	(1206 case size)
	1200 Case size)

\	200 0000 0.20)						
定格電圧	形名	公 称 静電容量	温度特性 Temperature	tan δ	実装条件 Soldering method	静電容量 許容差	厚 み Thickness
RatedVoltage	Ordering code	Capacitance [µF]	characteristics		R:リフロー Reflow soldering W:フロー Wave soldering		[mm] (inch)
10V	LMK316BJ225MD	2.2	BJ/X7R	3.5			0.85±0.1 (0.033±0.004)
100	LMK316BJ335MF	3.3	Do/X/11	0.0			1.15±0.1 (0.045±0.004)
	JMK316BJ335MD	3.3			R	±20%	0.85±0.1 (0.033±0.004)
6.3V	JMK316BJ475MD	4.7	BJ/X5R	5			(0.000_0.1)
	JMK316BJ685MF	6.8					1.15±0.1 (0.045±0.004)
10V	LMK316F475ZD	4.7		9		+80%	0.85±0.1 (0.033±0.004)
100	LMK316F106ZF	10	F/Y5V	16	R	-20%	1.15±0.1 (0.045±0.004)
6.3V	JMK316F106ZD	10		10		20%	0.85±0.1 (0.033±0.004)

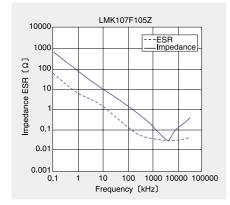
■325TYPE(1210	case size)
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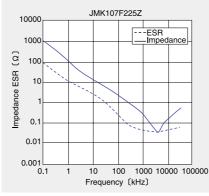
	,						
定格電圧	形名	公 称 静電容量	温度特性 Temperature	tan δ	実装条件 Soldering method	静電容量 許容差	厚 み Thickness
RatedVoltage	Ordering code	Capacitance [µF]	characteristics		R:リフロー Reflow soldering W:フロー Wave soldering	Capacitance tolerance	[mm] (inch)
10V	LMK325BJ335MD	3.3	BJ/X7R	3.5			0.85±0.1 (0.033±0.004)
100	LMK325BJ475MF	4.7	DO/X/11	3.3	R	±20%	1.15±0.1 (0.045±0.004)
6.3V	JMK325BJ106MF	10	BJ/X5R	5			(0.0.0_0.00)
0.34	JMK325BJ106MD	10	DO/XOI1	3			0.85±0.1 (0.033±0.004)
16V	EMK325F106ZF	10	F/Y5V	7	R	+80%	1.15±0.1 (0.045±0.004)
10V	LMK325F226ZF	22	1,130	16		-20%	

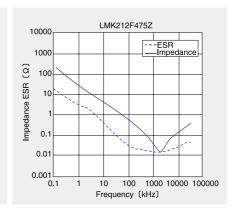
特性図 ELECTRICAL CHARACTERISTICS

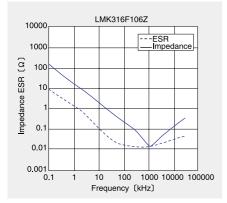
インピーダンス・ESR-周波数特性例 Example of Impedance ESR vs. Frequency characteristics

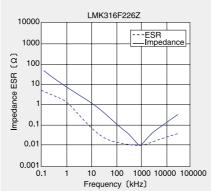
・当社積層セラミックコンデンサ例 (Taiyo Yuden multilayer ceramic capacitor)

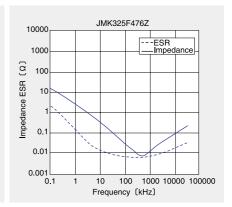


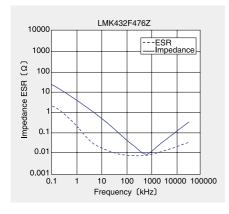


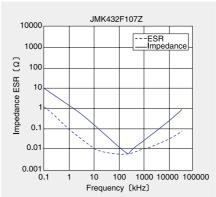


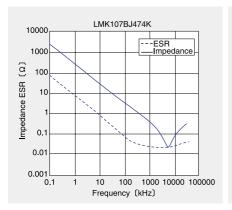


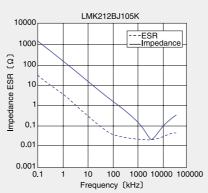


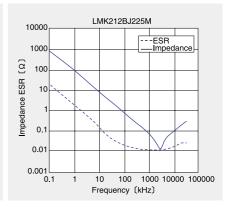


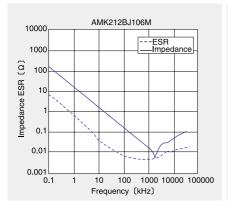


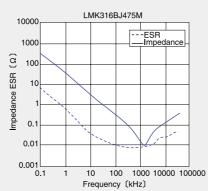


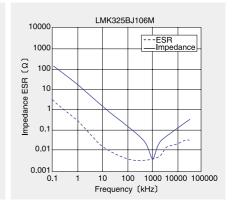


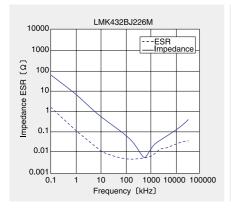


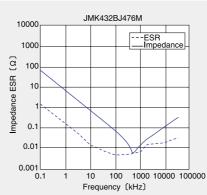


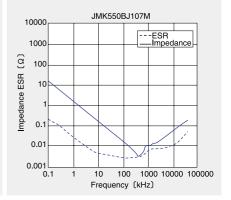












Multilayer Ceramic Capacitor Chips

			Specific	ed Value			
li	tem	Temperature Com	pensating (Class 1)	High Permit	vity (Class 2)	Test Methods and Remarks	
		Standard	High Frequency Type	Standard Note1	High Value		
1.Operating Range	Temperature	-55 to +125℃		B: −55 to +125°C F: −25 to +85°C	-25 to +85℃	High Capacitance Type BJ(X7R): -55 to +125°C BJ(X5R): -55 to +85°C	
2.Storage	Temperature	-55 to +125℃		B: −55 to +125°C	-25 to +85℃	F(Y5V): -30 to +85°C High Capacitance Type BJ(X7R): -55 to +125°C BJ(X5R): -55 to +85°C	
Range 3.Rated Volta	ne.	50VDC,25VDC,	16VDC	F: -25 to +85°C 50VDC,25VDC	50VDC,35VDC,25VDC	F(Y5V): −30 to +85°C	
s.nateu voita	ge	16VDC	TOVE	30VDC,23VDC	16VDC,10VDC,6.3VDC 4DVC		
4.Withstandin	g Voltage	No breakdown or dam-	No abnormality	No breakdown or dama	ge	Applied voltage: Rated voltage×3 (Class 1)	
Between ter	rminals	age				Rated voltage×2.5 (Class 2) Duration: 1 to 5 sec. Charge/discharge current: 50mA max. (Class 1,2)	
5.Insulation F	lesistance	10000 MΩ min.		smaller.	$M\Omega .,$ whichever is the	Applied voltage: Rated voltage Duration: 60±5 sec.	
6 Canasitana	e (Tolerance)	0.5 to 5 pF: ±0.25 pF	0.5 to 2 pF : ±0.1 pF	Note 4 B: ±10%, ±20%	BJ: ±10%, ±20%	Charge/discharge current: 50mA max. Measuring frequency:	
о.Сараснапо	e (Tolerance)	1 to 10pF: ±0.5 pF 5 to 10 pF: ±1 pF 11 pF or over: ±5% ±10% 10sTYPERA, SA, TA, UA only 0.5~2pF: ±0.1pF 2.2~20pF: ±5%	2.2 to 5.1 pF : ±5%	F: +80 %	F: +80%, ±20% F: +20 %	Class1: $1 \text{MHz} \pm 10\% (\text{C} \le 1000 \text{pF})$ $1 \text{ k Hz} \pm 10\% (\text{C} > 1000 \text{pF})$ $1 \text{ k Hz} \pm 10\% (\text{C} > 1000 \text{pF})$ $1 \text{ k Hz} \pm 10\% (\text{C} \le 22_{\mu} \text{F})$ $120 \text{Hz} \pm 10 \text{Hz} (\text{C} \le 22_{\mu} \text{F})$ Measuring voltage: $\text{Class1: 0.5} \sim 5 \text{Vrms} (\text{C} \le 1000 \text{pF})$ $1 \pm 0.2 \text{Vrms} (\text{C} > 1000 \text{pF})$ $1 \pm 0.2 \text{Vrms} (\text{C} > 1000 \text{pF})$ $0.5 \pm 0.1 \text{Vrms} (\text{C} > 22_{\mu} \text{F})$ Bias application: None	
7.Q or Tangen (tan δ)	it of Loss Angle	Under 30 pF : Q≥400 + 20C 30 pF or over : Q≥1000 C= Nominal capacitance	Refer to detailed specification	B: 2.5% max.(50V, 25V) F: 5.0% max. (50V, 25V)	BJ: 2.5% max. (50V, 35V, 25V) 3.5% max. % 5.0% max. % 10.0% max. % F: 7.0% max. 5.0% max. % 9.0% max. % 11.0% max. % 16.0% max. % 20.0% max. % % See Table.1	Multilayer: Measuring frequency: Class1: $1 \text{MHz} \pm 10\% (\text{C} \le 1000 \text{pF})$ $1 \text{ k Hz} \pm 10\% (\text{C} > 1000 \text{pF})$ $1 \text{ k Hz} \pm 10\% (\text{C} > 1000 \text{pF})$ $1 \text{ k Hz} \pm 10\% (\text{C} \le 22 \mu \text{F})$ $12 \text{OHz} \pm 10 \text{Hz} (\text{C} \ge 22 \mu \text{F})$ Measuring voltage: Class1: $0.5 \sim 5 \text{Vrms} (\text{C} \le 1000 \text{pF})$ $1 \pm 0.2 \text{Vrms} (\text{C} > 1000 \text{pF})$ $1 \pm 0.2 \text{Vrms} (\text{C} > 1000 \text{pF})$ $1 \pm 0.2 \text{Vrms} (\text{C} \ge 22 \mu \text{F})$ $0.5 \pm 0.1 \text{Vrms} (\text{C} \ge 22 \mu \text{F})$ $0.5 \pm 0.1 \text{Vrms} (\text{C} > 22 \mu \text{F})$ Bias application: None $1 \text{High-Frequency-Multilayer:}$ Measuring frequency: 1 GHz Measuring equipment: 1HP4291A Measuring ig: 1HP16192A	
8.Temperature Characteristic of Capacitance	(Without voltage application)	CK: 0±250 CJ: 0±120 CH: 0±60 CG: 0±30 PK: -150±250 PJ: -150±120 PH: -150±60 RK: -220±250 RJ: -220±120 RH: -220±60 SK: -330±250 SJ: -330±120 SH: -330±60 TK: -470±250 TJ: -470±120 TH: -470±60 UK: -750±250 UJ: -750±120	CH: 0±60 RH: -220±60 (ppm/C)	B:±10%(-25~85°) F: +30 %(-25~85°) B(X7R):±15% F(Y5V): +82 %	BJ: ±10%(-25~85°C) F: +30 % (-25~85°C) BJ(X7R,XSR): ±15% F(Y5V): +22 %	According to JIS C 5102 clause 7.12. Temperature compensating: Measurement of capacitance at 20°C and 85°C shall be mad to calculate temperature characteristic by the following equation. (Cess - C20) C20 × ΔT × 10 6 (ppm/C) High permittivity: Change of maximum capacitance deviation in step 1 to Temperature at step 1: +20°C Temperature at step 2: minimum operating temperature Temperature at step 3: +20°C (Reference temperature) Temperature at step 4: maximum operating temperature Temperature at step 5: +20°C Reference temperature for X7R, X5R and Y5V shall be +25°C	
9.Resistance Substrate	to Flexure of	SL: +350 to -1000 (ppm/C) Appearance: No abnormality Capacitance change: Within ±5% or ±0.5 pF, whichever is larger.	Appearance: No abnormality Capacitance change: Within±0.5 pF	Appearance: No abnormality Capacitance change: B, BJ: Within ±12.5% F: Within ±30%		Warp: 2mm Testing board: paper-phenol substrate Thickness: 1.6mm The measurement shall be made with board in the bent position Board Warp Warp (Unit: mm)	

Multilayer Ceramic Capacitor Chips

		Specifie	d Value		Test Methods and Remarks		
Item	Temperature Com	pensating (Class 1)	High Permitt	vity (Class 2)			
	Standard	High Frequency Type	Standard Note1	High Value			
10.Body Strength	_	No mechanical damage.	_	_	High Frequency Multilayer: Applied force: 5N Duration: 10 sec. Press Chip L L W		
11.Adhesion of Electrode	No separation or indication of separation of electrode.				Applied force: 5N Duration: 30±5 sec. Hooked jig Chip Cross-section		
12.Solderability	At least 95% of terminal	electrode is covered by n	Solder temperature: 230±5°C Duration: 4±1 sec.				
13.Resistance to soldering	Appearance: No abnor-	Appearance: No abnor-	Appearance: No abnorm	aclity	Preconditioning: Thermal treatment (at 150°C for 1 hr)		
	mality Capacitance change: Within $\pm 2.5\%$ or $\pm 0.25 pF$, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	or Within ±2.5% is Q: Initial value Insulation resistance: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality tan δ: Initial value Insulation resistance: Initial value withstanding voltage (between terminals): No abnormality		vithin ±20% (F)	(Applicable to Class 2.) Solder temperature: 270±5°C Duration: 3±0.5 sec. Preheating conditions: 80 to 100°C, 2 to 5 min. or 5 to 10 min. 150 to 200°C, 2 to 5 min. or 5 to 10 min. Recovery: Recovery for the following period under the standard condition after the test. 24±2 hrs (Class 1) 48±4 hrs (Class 2)		
14.Thermal shock	Appearance: No abnormality Capacitance change: Within ± 2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±0.25pF Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Capacitance change: Within ±7.5% (B, BJ) Within ±20% (F) tan \$\varepsilon\$: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality		Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Conditions for 1 cycle: Step 1: Minimum operating temperature 30±3 min. Step 2: Room temperature 15 min. Step 3: Maximum operating temperature 30±3 min. Step 4: Room temperature 15 min. Number of cycles: 5 times Recovery after the test: 24±2 hrs (Class 1) 48±4 hrs (Class 2)		
15.Damp Heat (steady state)	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5pF, whichever is larger. Q: C≥30 pF : Q≥350 10≤C<30 pF: Q≥275 +2.5C C<10 pF : Q≥200 + 10C C: Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within $\pm 0.5 pF$, Insulation resistance: 1000 M Ω min.	Appearance: No abnormality Capacitance change: B: Within $\pm 12.5\%$ F: Within $\pm 30\%$ tan δ : B: 5.0% max. F: 7.5% max. Insulation resistance: 50 M Ω μ F or 1000 M Ω whichever is smaller.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ $\tan \delta$: BJ: 5.0% max. 7.5% max.** 20.0% max.** F: 11.0% max. 7.5% max.** 16.0% max.** 19.5% max.** 25.0% max.** 25.0% max.** 25.0% max.** 3 See Table.2 Insulation resistance: $\tan \mu = 1000$ M μ F or 1000 M μ C whichever is smaller.	Multilayer: Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Temperature: 40±2°C Humidity: 90 to 95% RH Duration: 500 *24 hrs Recovery: Recovery for the following period under the star dard condition after the removal from test chamber. 24±2 hrs (Class 1) 48±4 hrs (Class 2) High-Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 *24 hrs Recovery: Recovery for the following period under the star dard condition after the removal from test chamber. 24±2 hrs (Class 1)		

Multilayer Ceramic Capacitor Chips

		Specifie			
Item	Temperature Comp	pensating (Class 1)	High Permitti	vity (Class 2)	Test Methods and Remarks
	Standard	High Frequency Type	Standard Note1	High Value	
6.Loading under Damp Heat	Appearance: No abnor-	Appearance: No abnor-	Appearance: No abnor-	Appearance: No abnor-	According to JIS C 5102 Clause 9. 9.
	mality	mality	mality	mality	Multilayer:
	Capacitance change:	Capacitance change:	Capacitance change:	Capacitance change:	Preconditioning: Voltage treatment (Class 2)
	Within ± 7.5% or	C≦2 pF: Within ±0.4 pF	B: Within ±12.5%	BJ: Within ± 12.5%	Temperature: 40±2℃
	±0.75pF, whichever is	C>2 pF: Within ±0.75	F: Within ±30%	(50V, 35V, 25V)	Humidity: 90 to 95% RH
	larger.	pF	tan δ: B: 5.0% max.	Within ±15.0% (16V	Duration: 500 ⁺²⁴ hrs
	Q: C≧30 pF: Q≧200	C: Nominal capaci-	F: 7.5% max.	and under)	Applied voltage: Rated voltage
	C<30 pF: Q≥100 +	tance		F: Within ±30%	Charge and discharge current: 50mA max. (Class 1,
	10C/3	Insulation resistance:	Insulation resistance:	tan δ: BJ: 5.0% max.	Recovery: Recovery for the following period under the star
	C: Nominal capaci-	500 MΩ min.	25 MΩ μ F or 500 MΩ,	7.5% max.*	condition after the removal from test chamber
	tance		whichever is the smaller.	20.0% max. **	24±2 hrs (Class 1)
	Insulation resistance:			F: 11.0% max.	48±4 hrs (Class 2)
	500 MΩ min.			7.5% max.*	High-Frequency Multilayer:
				16.0% max.*	Temperature: 60±2℃
				19.5% max.*	Humidity: 90 to 95% RH
				25.0% max.*	Duration: 500 $^{+24}_{-0}$ hrs
				*See Table.2	
				Insulation resistance:	Charge and discharge current: 50mA max.
				25 MΩ μF or 500 MΩ,	Recovery: 24±2 hrs of recovery under the standard of
				whichever is the smaller.	tion after the removal from test chamber.
7.Loading at High Tempera-	Appearance: No abnor-	Appearance: No abnor-	Appearance: No abnor-	Appearance: No abnormality	According to JIS C 5102 clause 9.10.
ture	mality	mality	mality	Capacitance change:	Multilayer:
	Capacitance change:	Capacitance change:	Capacitance change:	BJ: Within ±12.5%	Preconditioning: Voltage treatment (Class 2)
	Within ±3% or	Within ±3% or	B: Within ±12.5%	F: Within ±30%	Temperature:125±3°C(Class 1, Class 2: B, BJ(X7R)
	±0.3pF, whichever is	±0.3pF, whichever is	F: Within ±30%	tan δ: 5.0% max.	85±2℃ (Class 2: BJ,F)
	larger.	larger.	tan δ:	7.5% max.*	Duration: 1000 +48 hrs
	Q: C≧30 pF : Q≧350	Insulation resistance:	B: 4.0% max.	20.0% max.*	Applied voltage: Rated voltage×2
	10≦C<30 pF: Q≧275	1000 MΩ min.	F: 7.5% max.	F: 11.0% max.	Recovery: Recovery for the following period under the
	+ 2.5C		Insulation resistance:	7.5% max.*	dard condition after the removal from test chamber.
	C<10 pF: Q≧200 +		50 MΩ μF or 1000 MΩ,	16.0% max.*	As for Ni product, thermal treatment shall be perfo
	10C		whichever is smaller.	19.5% max.*	prior to the recovery.
	C: Nominal			25.0% max.*	24±2 hrs (Class 1)
	capacitance			*See Table.2	48±4 hrs (Class 2)
	Insulation resistance:			Insulation resistance: 50	High-Frequency Multilayer:
	1000 MΩ min.			MΩμF or 1000 $MΩ$, which-	Temperature: 125±3°C (Class 1)
				ever is smaller.	Duration: 1000 ⁺⁴⁸ ₋₀ hrs
					Applied voltage: Rated voltage×2
					Recovery: 24±2 hrs of recovery under the standard c
				l	

Note 1: For 105 type, specified in "High value".

Note 2: Thermal treatment (Multilayer): 1 hr of thermal treatment at 150 +0 /-10 °C followed by 48±4 hrs of recovery under the standard condition shall be performed before the measurement.

Note 3: Voltage treatment (Multilayer): 1 hr of voltage treatment under the specified temperature and voltage for testing followed by 48±4 hrs of recovery under the standard condition shall be performed before the measurement. Note on standard condition "standard condition" referred to herein is defined as follows: 5 to 35°C of temperature, 45 to 85% relative humidity, and 86 to 106kPa of air pressure.

When there are questions concerning measurement results: In order to provide correlation data, the test shall be conducted under condition of 20±2°C of temperature, 65 to 70% relative humidity, and 86 to 106kPa of air pressure. Unless otherwise specified, all the tests are conducted under the "standard condition."

Note 4: Specified value for Instration Resistance of JMK212BJ475M only: 100MΩ μF or more.

Table. 1 tanδ(D. F.)

Item	tan∂
BJ: LMK type; 063 type 105 type ($C \le 0.047 \mu\text{F}$) 107 type ($C \le 0.47 \mu\text{F}$) 107 type ($C \le 1.47 \mu\text{F}$) 212 type ($C \le 1.47 \mu\text{F}$) 316 / 325 / 432 type EMK type; 105 / 107/212 / 316 / 325 type TMK type; 316 type($C > 0.47 \mu\text{F}$) 325 / 432 type	3.5%max.
GMK type;212 type ($C \ge 0.22 \mu F$) 316 type ($C \ge 0.68 \mu F$) 325 type UMK type;212 type ($C > 0.1 \mu F$) 316 type ($C \ge 0.47 \mu F$) 325 type ($C \le 1.47 \mu F$)	
BJ: JMK type LMK type; 105 type (C≧0.056 µF)	
107 type ($C > 0.47 \mu F$) 212 type ($C > 1 \mu F$)	5.0% max.
J4K, E4K type F: 105 type (50V, 25V)	
F: LMK type; 212 type 316 type (C=10 μF):汎用	
130 type (C=4.7μF): ///π/π/π/π/π/π/π/π/π/π/π/π/π/π/π/π/π/π	9.0% max.
BJ: AMK type	10.0% max.
F: LMK type; 105 type (C =0.22 μF)	11.0% max.
F: JMK type; 105 / 107 / 212 / 316 / 325 / 432 type LMK type; 107 type,325 type 432 type,316 type (C > 10 \(\mu \)F)	16.0% max.
E4K type F: AMK type	20.0% max.

Table. 2 tanδ(D. F.)

Item	$tan \delta$
BJ: JMK type	
LMK type; 063 type	
105 type (C≧0.056 μF)	
107 type (C≧0.47 μF)	7.5% max.
212 type (C > 1 μF)	
J4K, E4K type	
F: 105 type(50V, 25V)	
F: LMK type; 105 type (C=0.22 µF)	16.0% max.
F: JMK type; 105 / 107 / 212 / 316 / 325 / 432 type	
LMK type; 107 type	19.5% max.
432 type	
E4K type	
BJ: AMK type	20.0% max.
F: AMK type	25.0% max.

梱包 PACKAGING

①標準数量 Standard quantity ■袋づめ梱包 Bulk packaging

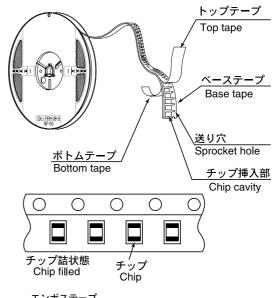
	t paonaging		
形式(EIA) Type	製品厚み Thickness		標準数量 Standard quantity
Турс	mm(inch)	code	[pcs]
☐MK105(0402)	0.5	V	
E VK105(0402)	(0.020)	W	
□MK107(0603)	0.8	A Z	
	(0.031) 0.85		
□MK212(0805)	(0.033)	D	
□IVIT(2 12(0003)	1.25 (0.049)	G	
□4K212(0805)	0.85 (0.033)	D	
	0.85 (0.033)	D	
□MK316(1206)	1.15 (0.045)	F	1000
_IVII(010(1200)	1.25 (0.049)	G	
	1.6 (0.063)	L	
□4K316(1206)	1.15 (0.045)	F	
	0.85 (0.033)	D	
	1.15 (0.045)	F	
□MK325(1210)	1.5 (0.059)	Н	
	1.9 (0.075)	N	
	2.5 (0.098)	М	

■テーピング梱包 Taped packaging

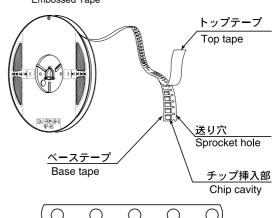
	raped packaging		+西:#	粉里
形式(EIA) Type	製品厚み Thickness		標準数量 Standard quantit [pcs]	
	mm(inch)	code	紙テープ paper	エンボステープ Embossed tape
☐MK063(0201)	0.3 (0.012)	Р	15000	
☐MK105(0402)	0.5	V		
E VK105(0402)	(0.020)	W	10000	_
□MK107(0603)	0.8	Α	4000	
IVIK 107 (0003)	(0.031)	Z	4000	
□MK212(0805)	0.85 (0.033)	D	4000	_
_IVII (2 12 (0000)	1.25 (0.049)	G	_	3000
□4K212(0805)	0.85 (0.033)	D	4000	_
	0.85 (0.033)	D	4000	_
□MK316(1206)	1.15 (0.045)	F		0000
	1.25 (0.049)	G	_	3000
	1.6 (0.063)	L		0000
□4K316(1206)	1.15 (0.045)	F	_	2000
	0.85 (0.033)	D		
	1.15 (0.045)	F		2000
□MK325(1210)	1.5 (0.059)	Н		2000
	1.9 (0.075)	N		
	2.5 (0.098)	М	_	500
☐MK432(1812)	2.5 (0.098)	М	_	500
□MK550(2220)	2.5 (0.098)	М	_	500

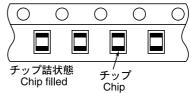
②テーピング材質 Taping material 紙テープ

Card board carrier tape

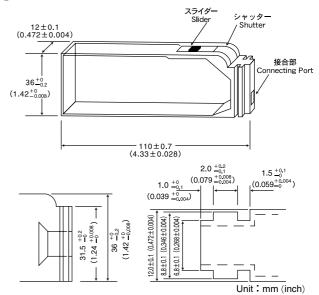


エンボステープ Embossed Tape



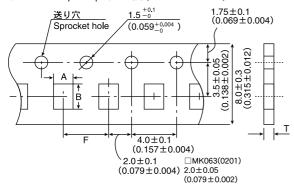


③バルクカセット Bulk Cassette



105, 107, 212形状で個別対応致しますのでお問い合せ下さい。 Please contact any of our offices for accepting your requirement according to dimensions 0402, 0603, 0805.(inch)

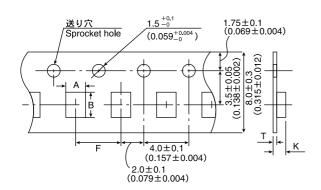
③テーピング寸法 Taping dimensions 紙テープ Paper Tape (8mm幅) (0.315inches wide)



Туре	チッフ	プ挿入部	挿入ピッチ	テープ厚み
(EIA)	Chip	Cavity	Insertion Pitch	Tape Thickness
	Α	В	F	Т
□MK063(0201)	0.37±0.06	0.67±0.06	2.0±0.05	0.42±0.02
□IVIKU63(U2U1)	(0.06±0.002)	(0.027±0.002)	(0.079±0.002)	(0.017±0.001)
☐MK105(0402)	0.65±0.1	1.15±0.1	2.0±0.05	0.8max.
E VK105(0402)	(0.026±0.004)	(0.045±0.004)	(0.079±0.002)	(0.031max.)
□MK107(0603)	1.0±0.2	1.8±0.2		
□IVIK 107 (0003)	(0.039±0.008)	(0.071±0.008)		
☐MK212(0805)	1.65±0.2	2.4±0.2	4.0±0.1	1.1max.
□4K212(0805)	(0.065±0.008)	(0.094±0.008)	(0.157±0.004)	(0.043max.)
□MK316(1206)	2.0±0.2	3.6±0.2		
	(0.079±0.008)	(0.142±0.008)		

Unit: mm(inch)

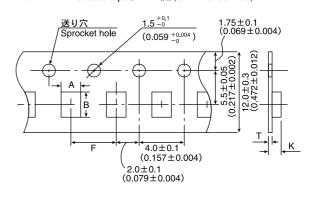
エンボステープ Embossed tape (8mm幅) (0.315inches wide)



Туре	チップ挿入部		挿入ピッチ	テーフ	プ厚み
(EIA)	Chip cavity		Insertion Pitch	Tape Th	ickness
	Α	В	F	K	Т
□MK212(0805)	1.65±0.2	2.4±0.2			
	(0.065±0.008)	(0.094±0.008)			
□MK316(1206)	2.0+0.2	3.6+0.2	4.0±0.1	2.5max.	0.6max
□4K316(1206)	(0.079±0.008)	(0.142±0.008)	(0.157±0.004)	(0.098max.)	(0.024max.)
□MK325(1210)	2.8±0.2	3.6±0.2		3.4max.	
□IVIR323(1210)	(0.110±0.008)	(0.142±0.008)		(0.134max.)	

Unit: mm(inch)

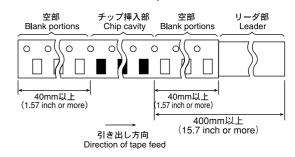
エンボステープ Embossed tape (12mm幅) (0.472inches wide)



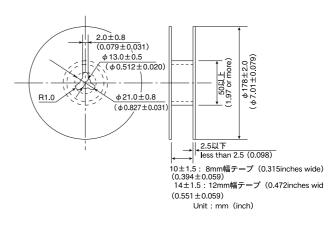
Туре	チップ挿入部		挿入ピッチ	テーフ	プ厚み
(EIA)	Chip cavity		Insertion Pitch	Tape Th	nickness
	A B		F	K	Т
□MK432(1812)	3.7±0.2 (0.146±0.008)	4.9±0.2 (0.193±0.008)	8.0±0.1 (0.315±0.004)	3.4max. (0.134max.)	0.6max. (0.024max.)
□MK550(2220)	5.4±0.2 (0.213±0.008)	6.1±0.2 (0.240±0.008)	8.0±0.1 (0.315±0.004)	3.5max. (0.138max.)	0.6max. (0.024max.)

Unit: mm(inch)

④リーダ部/空部 Leader and Blank portion

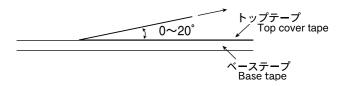


⑤リール寸法 Reel size



⑥トップテープ強度 Top Tape Strength

トップテープのはがし力は下図矢印方向に τ 0.1 \sim 0.7Nとなります。 The top tape requires a peel-off force of 0.1 \sim 0.7N in the direction of the arrow as illustrated below.



Stages	Precautions	Technical considerations
1.Circuit Design	Verification of operating environment, electrical rating and performance 1. A malfunction in medical equipment, spacecraft, nuclear reactors, etc. may cause serious harm to human life or have severe social ramifications. As such, any capacitors to be used in such equipment may require higher safety and/or reliability considerations and should be clearly differentiated from components used in general purpose applications. Operating Voltage (Verification of Rated voltage) 1. The operating voltage for capacitors must always be lower than their rated values. If an AC voltage is loaded on a DC voltage, the sum of the two peak voltages should be lower than the rated value of the capacitor chosen. For a circuit where both an AC and a pulse voltage may be present, the sum of their peak voltages should also be lower than the capacitor's rated voltage. 2. Even if the applied voltage is lower than the rated value, the reliability of capacitors might be reduced if either a high frequency AC voltage or a pulse voltage having rapid rise time is present in the circuit.	
2.PCB Design	Pattern configurations (Design of Land-patterns) 1. When capacitors are mounted on a PCB, the amount of solder used (size of fillet) can directly affect capacitor performance. Therefore, the following items must be carefully considered in the design of solder land patterns: (1) The amount of solder applied can affect the ability of chips to withstand mechanical stresses which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads which in turn determines the amount of solder necessary to form the fillets. (2) When more than one part is jointly soldered onto the same land or pad, the pad must be designed so that each component's soldering point is separated by solder-resist.	1.The following diagrams and tables show some examples of recommended patterns to prevent excessive solder amourts.(larger fillets which extend above the component end terminations) Examples of improper pattern designs are also shown. (1) Recommended land dimensions for a typical chip capacitor land patterns for PCBs Land pattern Chip capacitor Chip capacitor Solder-resist Chip capacitor Chip capacitor Chip capacitor Chip capacitor Solder-resist Chip capacitor Type 107 212 316 325 A 0.8~1.0 1.0~1.4 1.8~2.5 1.8~2.5 B 0.5~0.8 0.8~1.5 0.8~1.7 0.8~1.7 C 0.6~0.8 0.9~1.2 1.2~1.6 1.8~2.5 Recommended land dimensions for reflow-soldering (unit: mm) Type 063 105 107 212 316 325 432 550 Recommended land dimensions for reflow-soldering (unit: mm) Type 063 105 107 212 316 325 432 550 A 0.20~0.30 0.45~0.55 0.6~0.8 0.8~1.2 1.8~2.5 1.8~2.5 2.5~3.5 3.7~4.7 B 0.20~0.30 0.45~0.55 0.6~0.8 0.8~1.2 1.8~2.5 1.8~2.5 2.5~3.5 3.7~4.7 B 0.20~0.30 0.45~0.55 0.6~0.8 0.8~1.2 1.8~2.5 1.8~2.5 2.5~3.5 3.5~5.5 Excess solder can affect the ability of chips to withstand mechanical stresses. Therefore, please take proper precautions when designing land-patterns. Chip Land pattern Type 316 (4 circuits) 212 (4 circuits) B 1.25 0.5~0.6 C 0.4~0.5 0.5~0.6 D 1.0.5~0.6 C 0.4~0.5 0.2~0.3

Stages	Precautions	Technical considerations		
2.PCB Design		(2) Examples of	of good and bad solder applicat	ion
		Items	Not recommended	Recommended
		Mixed mounting of SMD and leaded components	Lead wire of component	Solder-resist
		Component placement close to the chassis	Chassis Solder(for grounding)	Solder-resist
		Hand-soldering of leaded components near mounted components	Lead wire of component- Soldering iron	Solder-resist
		Horizontal component placement		Solder-resist
	Pattern configurations (Capacitor layout on panelized [breakaway] PC boards) 1. After capacitors have been mounted on the boards, chips can	_		capacitor layout; SMD capacitors should at stresses from board warp or deflection.
	be subjected to mechanical stresses in subsequent manufac-		Not recommended	Recommended
	turing processes (PCB cutting, board inspection, mounting of additional parts, assembly into the chassis, wave soldering the reflow soldered boards etc.) For this reason, planning pattern configurations and the position of SMD capacitors should be carefully performed to minimize stress.	Deflection of the board		Position the component at a right angle to the rection of the mechanical stresses that are anticipated.
	should be early performed to minimize stress.	1-2. To layout the c	apacitors for the breakaway PC	board, it should be noted that the amount
			•	ding on capacitor layout. The example
		below shows re	commendations for better desi	gn.
		Perforati	on C Slit Magnitude of stress	D 0000 B A>B = C>D>E
		the capacitors of	an vary according to the methodast stressful to most stressful:	ions, the amount of mechanical stress on d used. The following methods are listed push-back, slit, V-grooving, and perfora- st also consider the PCB splitting proce-

dure.

Stages	Precautions	Technical considerations		
3.Considerations for automatic placement	Adjustment of mounting machine 1. Excessive impact load should not be imposed on the capacitors when mounting onto the PC boards. 2. The maintenance and inspection of the mounters should be conducted periodically.	capacitors, cau before lowering (1)The lower limit board after corr (2)The pick-up pr (3)To reduce the a supporting pins	sing damage. To avoid this, the the pick-up nozzle: of the pick-up nozzle should be a vecting for deflection of the board amount of deflection of the board of the deflection of the board of the deflection of the board of	en 1 and 3 N static loads. caused by impact of the pick-up nozzle, under the PC board. The following dia-
			Not recommended	Recommended
		Single-sided mounting	Cracks	Supporting pin-k
		Double-sided mounting	Solder peeling Cracks	Supporting pin
		cracking of the	capacitors because of mechanic	ne nozzle height can cause chipping or cal impact on the capacitors. To avoid nment pin in the stopped position, and pin should be conducted periodically.
	Selection of Adhesives 1. Mounting capacitors with adhesives in preliminary assembly, before the soldering stage, may lead to degraded capacitor characteristics unless the following factors are appropriately checked; the size of land patterns, type of adhesive, amount applied, hardening temperature and hardening period. Therefore, it is imperative to consult the manufacturer of the adhesives on proper usage and amounts of adhesive to use.	shrinkage percor on the capacito to the board many should be noted. (1)Required adhe a. The adhesive solder process. b. The adhesive solder the adhesive solder the adhesive solder. The adhesive solder the adhesive solder.	entage of the adhesive and that o rs and lead to cracking. Moreover ay adversely affect component pla d in the application of adhesives. sive characteristics hould be strong enough to hold pa	kness consistency.
		h. The adhesive s	should have excellent insulation of	mission of toxic gasses.
			nded amount of adhesives is as fo	·
		Figure	212/316 case size	Р 11
		b a	0.3mm 100 ~12	
		С	Adhesives should no	
		Amou	nt of adhesive	After capacitors are bonded

Stages	Precautions	Technical considerations
. Soldering	Selection of Flux 1. Since flux may have a significant effect on the performance of capacitors, it is necessary to verify the following conditions prior to use; (1)Flux used should be with less than or equal to 0.1 wt% (equivelent to chroline) of halogenated content. Flux having a strong acidity content should not be applied. (2)When soldering capacitors on the board, the amount of flux applied should be controlled at the optimum level. (3)When using water-soluble flux, special care should be taken to properly clean the boards.	1-1. When too much halogenated substance (Chlorine, etc.) content is used to activate the flux, or highly acidic flux is used, an excessive amount of residue after soldering may lead to corrosion of the terminal electrodes or degradation of insulation resistance on the surface of the capacitors. 1-2. Flux is used to increase solderability in flow soldering, but if too much is applied, a large amount of flux gas may be emitted and may detrimentally affect solderability. To minimize the amount of flux applied, it is recommended to use a flux-bubbling system. 1-3. Since the residue of water-soluble flux is easily dissolved by water content in the air, the residue on the surface of capacitors in high humidity conditions may cause a degradation of insulation resistance and therefore affect the reliability of the components. The cleaning methods and the capability of the machines used should also be considered carefully when selecting water-soluble flux.
	Soldering Temperature, time, amount of solder, etc. are specified in accordance with the following recommended conditions.	1-1. Preheating when soldering Heating: Ceramic chip components should be preheated to within 100 to 130°C of the soldering. Cooling: The temperature difference between the components and cleaning process should not be greater than 100°C. Ceramic chip capacitors are susceptible to thermal shock when exposed to rapid or concentrated heating or rapid cooling. Therefore, the soldering process must be conducted with great care so as to prevent malfunction of the components due to excessive thermal shock.
		Recommended conditions for soldering [Reflow soldering] Temperature profile
		Temperature (C) 300 200 150 100 Ver 1 minute Over 1 minute Wiffin Gradual 100 seconds Caution
		The ideal condition is to have solder mass (fillet) controlled to 1/2 to 1/3 of the thickness of the capacitor, as shown below: Capacitor Capacitor PC board PC board
		Because excessive dwell times can detrimentally affect solderability, soldering duration should be kept as close to recommended times as possible.
		[Wave soldering] Temperature profile Temperature (C) 300 250 Preheating 230°C 250°C 250°
		Caution 1. Make sure the capacitors are preheated sufficiently. 2. The temperature difference between the capacitor and melted solder should not be greater than 100 to130°C 3. Cooling after soldering should be as gradual as possible. 4. Wave soldering must not be applied to the capacitors designated as for reflow soldering only.

Stages	Precautions	Technical considerations
4. Soldering		[Hand soldering] Temperature profile Temperature (C) 300 Preheating -280°C -2
		Use a 20W soldering iron with a maximum tip diameter of 1.0 mm. The soldering iron should not directly touch the capacitor.
5.Cleaning	Cleaning conditions When cleaning the PC board after the capacitors are all mounted, select the appropriate cleaning solution according to the type of flux used and purpose of the cleaning (e.g. to remove soldering flux or other materials from the production process.) Cleaning conditions should be determined after verifying, through a test run, that the cleaning process does not affect the capacitor's characteristics.	1. The use of inappropriate solutions can cause foreign substances such as flux residue to adhere to the capacitor or deteriorate the capacitor's outer coating, resulting in a degradation of the capacitor's electrical properties (especially insulation resistance). 2. Inappropriate cleaning conditions (insufficient or excessive cleaning) may detrimentally affect the performance of the capacitors. (1) Excessive cleaning In the case of ultrasonic cleaning, too much power output can cause excessive vibration of the PC board which may lead to the cracking of the capacitor or the soldered portion, or decrease the terminal electrodes' strength. Thus the following conditions should be carefully checked;
		Ultrasonic output Below 20 W/ℓ Ultrasonic frequency Below 40 kHz Ultrasonic washing period 5 min. or less
6.Post cleaning processes	1. With some type of resins a decomposition gas or chemical reaction vapor may remain inside the resin during the hardening period or while left under normal storage conditions resulting in the deterioration of the capacitor's performance. 2. When a resin's hardening temperature is higher than the capacitor's operating temperature, the stresses generated by the excess heat may lead to capacitor damage or destruction. The use of such resins, molding materials etc. is not recommended.	
7.Handling	Breakaway PC boards (splitting along perforations) 1. When splitting the PC board after mounting capacitors and other components, care is required so as not to give any stresses of deflection or twisting to the board. 2. Board separation should not be done manually, but by using the appropriate devices.	
	Mechanical considerations 1. Be careful not to subject the capacitors to excessive mechanical shocks. (1) If ceramic capacitors are dropped onto the floor or a hard surface, they should not be used. (2) When handling the mounted boards, be careful that the mounted components do not come in contact with or bump against other boards or components.	

Stages	Precautions	Technical considerations
8.Storage conditions	Storage 1. To maintain the solderability of terminal electrodes and to keep the packaging material in good condition, care must be taken to control temperature and humidity in the storage area. Humidity should especially be kept as low as possible. Recommended conditions Ambient temperature Below 40°C Humidity Below 70% RH The ambient temperature must be kept below 30°C. Even under ideal storage conditions capacitor electrode solderability decreases as time passes, so ceramic chip capacitors should be used within 6 months from the time of delivery. The packaging material should be kept where no chlorine or sulfur exists in the air. 2. The capacitance value of high dielectric constant capacitors (type 2 &3) will gradually decrease with the passage of time, so this should be taken into consideration in the circuit design. If such a capacitance reduction occurs, a heat treatment of 150°C for 1hour will return the capacitance to its initial level.	If the parts are stored in a high temperature and humidity environment, problems such as reduced solderability caused by oxidation of terminal electrodes and deterioration of taping/packaging materials may take place. For this reason, components should be used within 6 months from the time of delivery. If exceeding the above period, please check solderability before using the capacitors.